

FGA70N33BTD 330V, 70A PDP IGBT

Features

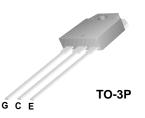
- High current capability
- Low saturation voltage: V_{CE(sat)} =1.7V @ I_C = 70A
- High input impedance
- · Fast switching
- RoHS Compliant

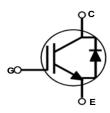
Applications

PDP System

General Description

Using Novel Trench IGBT Technology, Fairchild's new series of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Description		Ratings	Units
V _{CES}	Collector to Emitter Voltage		330	V
V _{GES}	Gate to Emitter Voltage		± 30	V
I _{Cpulse(1)} *	Pulsed Collector Current	⊉ T _C = 25°C	160	А
I _{C pulse(2)} *	Pulsed Collector Current	⊉ T _C = 25°C	220	А
P _D	Maximum Power Dissipation	⊉ T _C = 25°C	149	W
' D	Maximum Power Dissipation	⊉ T _C = 100°C	60	W
V _{RRM}	Peak Repetitive Reverse Voltage of Diode		330	V
I _{F(AV)}	Average Rectified Forward Current of diode @ $T_C = 100^{\circ}C$		10	А
I _{FSM}	Non-repetitive Peak Surge Current of diode 60Hz Single Half-Sine wave		100	A
T _J , T _{stg}	Operating Junction Temperature and Storage Temperrature		-55 to +150	°C
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance, Junction to Case		0.84	°C/W
$R_{\theta JC}$ (Diode)	Thermal Resistance, Junction to Case		1.16	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient		40	°C/W

Notes:

1: Repetitive test , Pulse width=100usec , Duty=0.1 2: Half Sine Wave, D< 0.01, pluse width < 5usec *I_C_pulse limited by max Tj

August 2011

Device N	vice Marking Device Pa		Package	Packaging ackage Type		Qty per Tube		Max Qty per Box	
		TO-3P	TO-3P Tube		30ea				
Electric	al Chai	acteristics of the	IGBT T _C =2	5°C unless otherwise noted	L		1		
Symbol		Parameter	Test	Conditions	Min.	Тур.	Max.	Units	
Off Charac	eristics								
BV _{CES}	Collector	to Emitter Breakdown Voltag	e V _{GE} = 0V, I _C	₂ = 250μA	330			V	
ΔB _{VCES} / ΔT _{.1}	Temperat Voltage	ure Coefficient of Breakdow		$V_{GE} = 0V, I_{C} = 250\mu A$		0.3		V/ºC	
ICES	Collector	Cut-Off Current	$V_{CE} = V_{CES}$, V _{GE} = 0V			250	μA	
I _{GES}	G-E Leak	age Current	$V_{GE} = V_{GES}$	s, V _{CE} = 0V			±400	nA	
On Charac	oristics		I						
V _{GE(th)}		shold Voltage	I _C = 250μA, V _{CE} = V _{GE}		2.3	3.3	4.3	V	
			-	I _C = 20A, V _{GE} = 15V		1.1		V	
	Collector	Collector to Emitter Saturation Voltage		I _C = 40A, V _{GE} = 15V,		1.4		V	
	Collector			$I_{C} = 70$ A, $V_{GE} = 15$ V, $T_{C} = 25^{o}$ C		1.7		V	
			I _C = 70A, V _C T _C = 125°C	I _C = 70A, V _{GE} = 15V, T _C = 125°C		1.8		V	
Dynamic C	haracteris	tics	I		1				
C _{ies}	Input Cap					1380		pF	
C _{oes}		apacitance	$V_{CE} = 30V, V_{GE} = 0V,$ f = 1MHz			140		pF	
C _{res}	Reverse ⁻	Fransfer Capacitance				60		pF	
Switching	Characteri	stics			1	1	L		
t _{d(on)}	Turn-On [Delay Time				13		ns	
t _r	Rise Time	9	$V_{CC} = 200V$			26		ns	
t _{d(off)}	Turn-Off [Delay Time	$\begin{array}{c} \hline \\ R_{G} = 5\Omega, V_{GE} = 15V, \\ \hline \\ Resistive Load, T_{C} = 25^{\circ}C \\ \hline \end{array}$			46		ns	
t _f	Fall Time					198		ns	
t _{d(on)}	Turn-On [Delay Time				13		ns	
t _r	Rise Time	;	$V_{CC} = 200V, I_C = 20A,$ $R_G = 5\Omega, V_{GE} = 15V,$ Resistive Load, $T_C = 125^{\circ}C$			28		ns	
t _{d(off)}	Turn-Off	Delay Time				48		ns	
t _f	Fall Time			-		268		ns	
Qg	Total Gate	e Charge				49		nC	
Q _{ge}	Gate to E	mitter Charge	$V_{CE} = 200V$, I _C = 20A,		6.8		nC	
Q _{gc}	Gate to C	ollector Charge	V _{GE} = 15V			17.5		nC	

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Symbol	Parameter	Parameter Test Conditions		Min.	Тур.	Max	Units
V _{FM} Diode Forward Voltage	Diode Forward Voltage	I _F = 10A	$T_{\rm C} = 25^{\rm o}{\rm C}$		1.1	1.5	V
	1 _F = 10/1	$T_{\rm C} = 125^{\rm o}{\rm C}$		0.95]	
t _{rr} Diode Reverse Recovery Time	Diode Reverse Recovery Time		$T_{\rm C} = 25^{\rm o}{\rm C}$		23		ns
		$T_{\rm C} = 125^{\rm o}{\rm C}$		36			
l	Diode Peak Reverse Recovery Current	I _F =10A, dI/dt = 200A/μs	$T_{\rm C} = 25^{\rm o}{\rm C}$		2.8		A
Irr			$T_{\rm C} = 125^{\rm o}{\rm C}$		5.1		
Q _{rr} Diode Reverse	Diode Reverse Recovery Charge		$T_{\rm C} = 25^{\rm o}{\rm C}$		32		nC
	Didde Reverse Receivery Onlarge		T 1050C		01		1

T_C = 125°C

91

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Typical Performance Characteristics



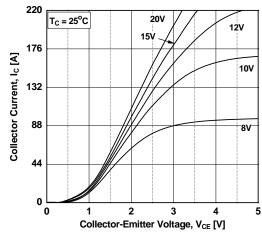


Figure 3. Typical Saturation Voltage Characteristics

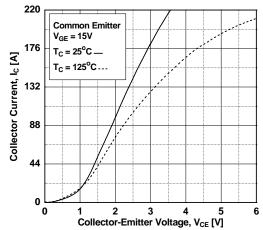


Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level

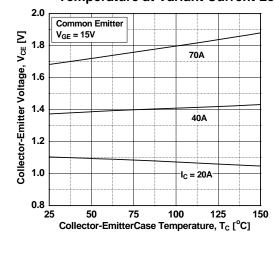


Figure 2. Typical Output Characteristics

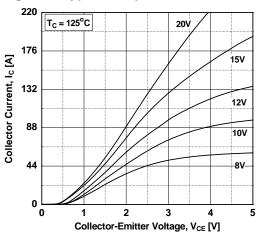


Figure 4. Transfer Characteristics

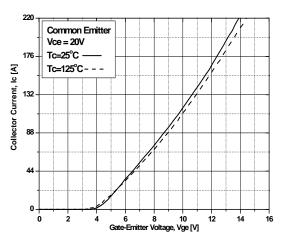


Figure 6. Saturation Voltage vs. V_{GE}

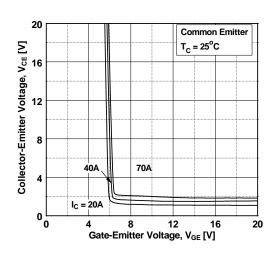
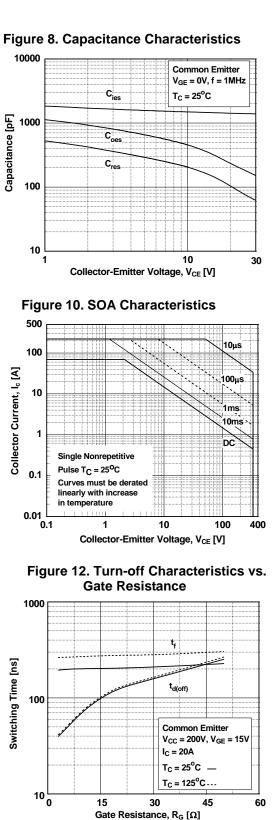
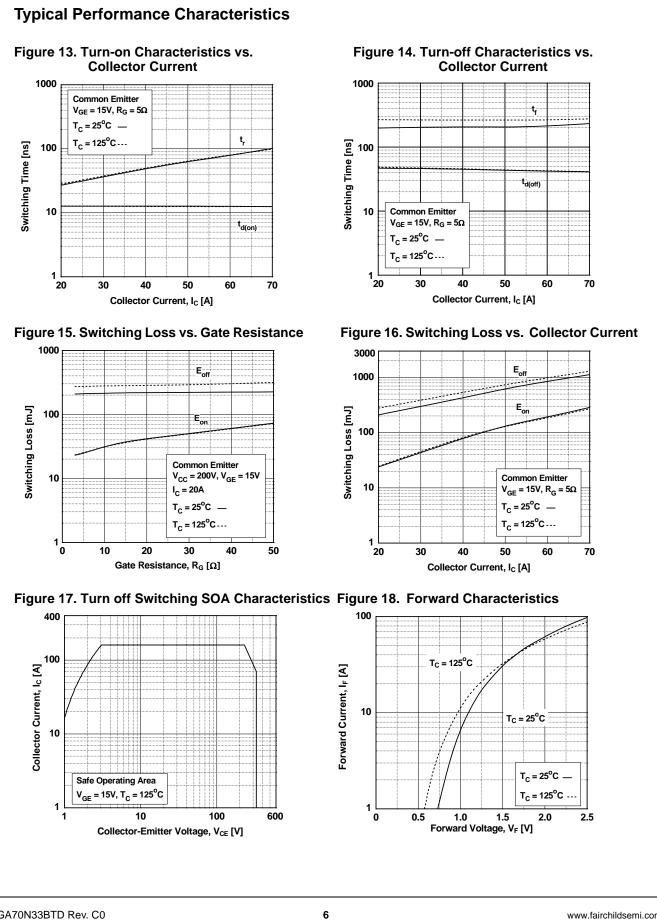


Figure 7. Saturation Voltage vs. V_{GE} 10000 20 Common Emitter $T_{\rm C} = 125^{\circ}C$ Capacitance [pF] 1000 100 40A 70A I_C = 20A 0 10 0 4 8 12 16 20 Gate-Emitter Voltage, V_{GE} [V] **Figure 9. Gate charge Characteristics** 15 500 Common Emitter $T_C = 25^{\circ}C$ 100 Gate-Emitter Voltage, V_{GE} [V] 8 0 6 7 $V_{CC} = 100V$ Collector Current, I_c [A] 10 200V 1 0.1 0 10 20 30 40 50 60 0 Gate Charge, Qg [nC] Figure 11. Turn-on Characteristics vs. **Gate Resistance** 200 100 t, Switching Time [ns] Switching Time [ns] 10 Common Emitter V_{CC} = 200V, V_{GE} = 15V I_C = 20A $T_{C} = 25^{\circ}C$ — T_C = 125°C 1 30 0 15 45 60 Gate Resistance, R_G [Ω]

Typical Performance Characteristics



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Typical Performance Characteristics

Figure 19. Reverse Recovery Current

Figure 20. Stored Charge

200A/µs

20

Forward Current, IF [A]

di/dt = 100A/µs

30

40

60

45

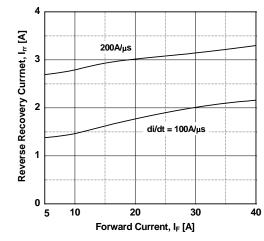
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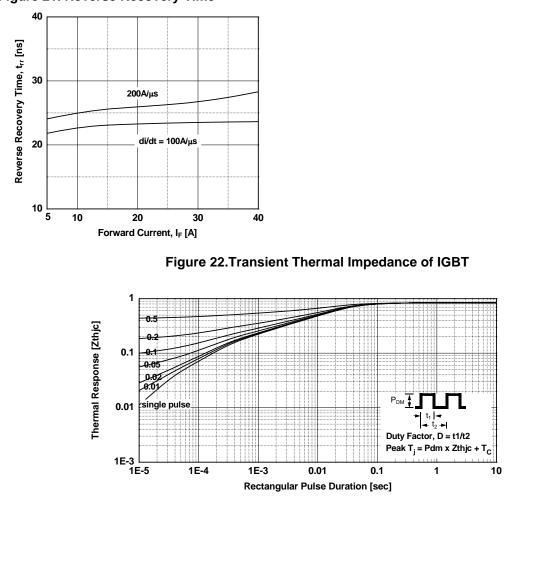
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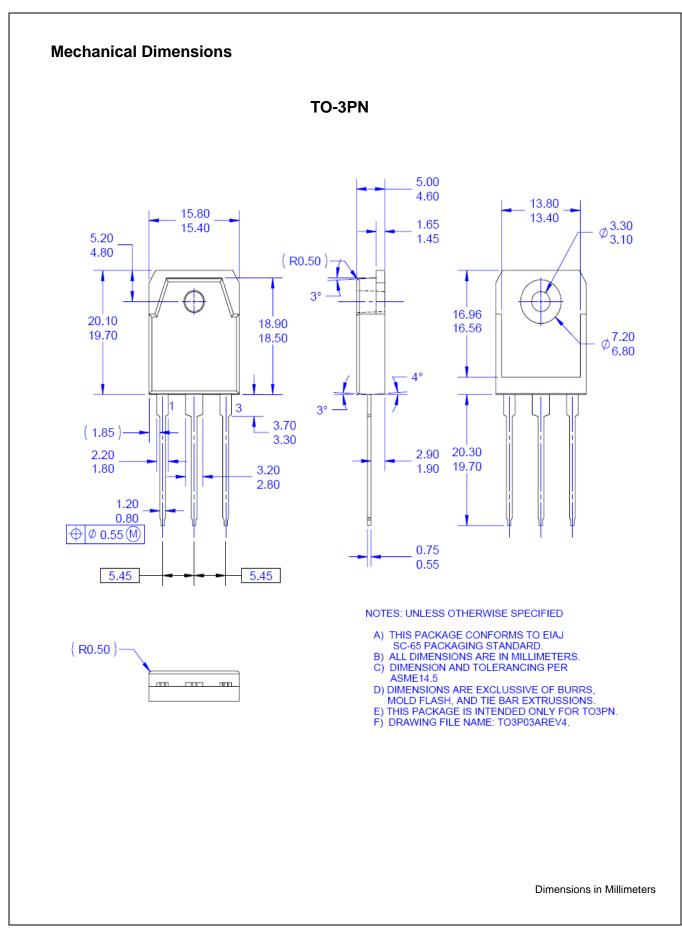
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Stored Recovery Charge, Qrr [nC]











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